Charles University Prague
Institute of Particle and Nuclear Physics

Laser Tests of Silicon Detectors

Peter Kodyš, Zdeněk Doležal, Jan Brož,
Pavel Řezníček, Zbyněk Drásal, Pavel Bažant,
Jan Poslušný

Progress of laser tests in Prague

1. Testing algorithms of strip detectors tuned
2. Set of standard tests and analysis: focusing, strip response, charge sharing
3. Different wavelengths: 650nm and 1060nm used
4. Angle (tilt) scans
5. Optical header for direct beam power measurements in progress
6. Simulations of laser beam in Si (Zbyněk Drásal talk)
7. Deeper understanding of laser beam interaction with Si detectors
8. DST data format for test beams prepared (are they good for laser tests?)
9. Preparing of analysis macros based on DST starting
10. Future plans/fields of interest

Testing algorithms of strip detectors

Complex test system integrates

- DAQ sw (VME – NI PCI-VME)
- oscilloscope (GPIB)
- pulse generator (GPIB)
- position stages 3D-2R (USB)
- 2x power supplies (USB-RS232)

ROOT based software allows

- High voltage (bias) checking
- Focusing algorithms – rough, fine
- Position scans
- Timing scans
- Tilted scans
- Tilted scans with deep focusing
- Environmental parameters monitoring (temperature, humidity, power drops, bias drops, remote access and full processing from any place (VNC), automatic emergency system

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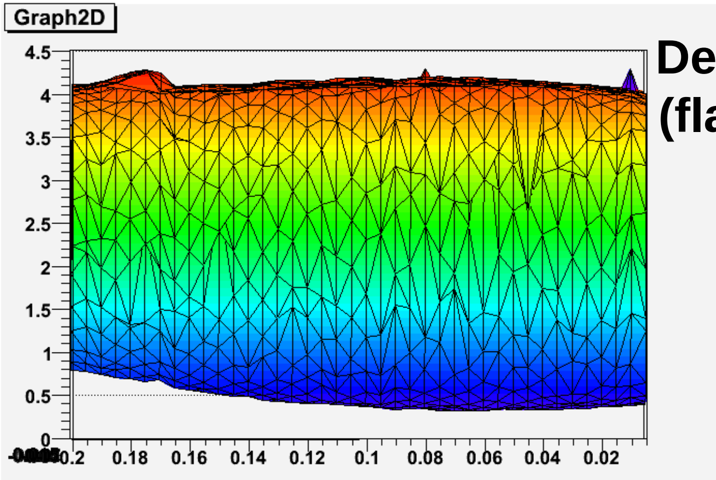
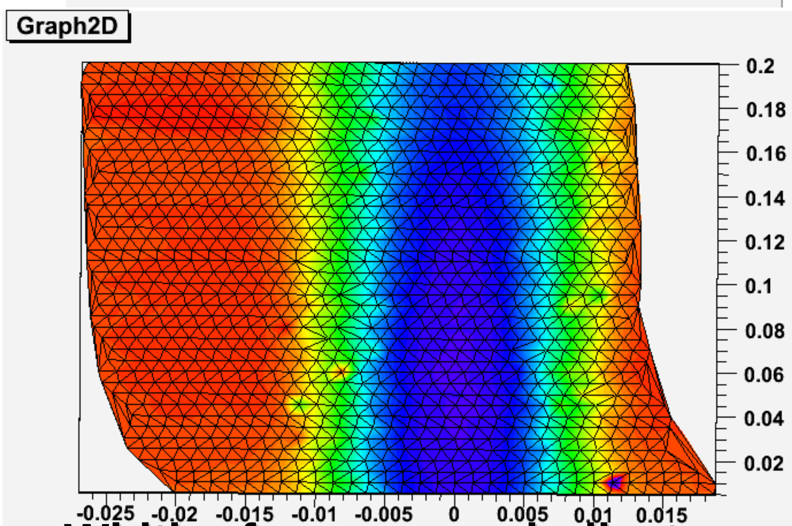
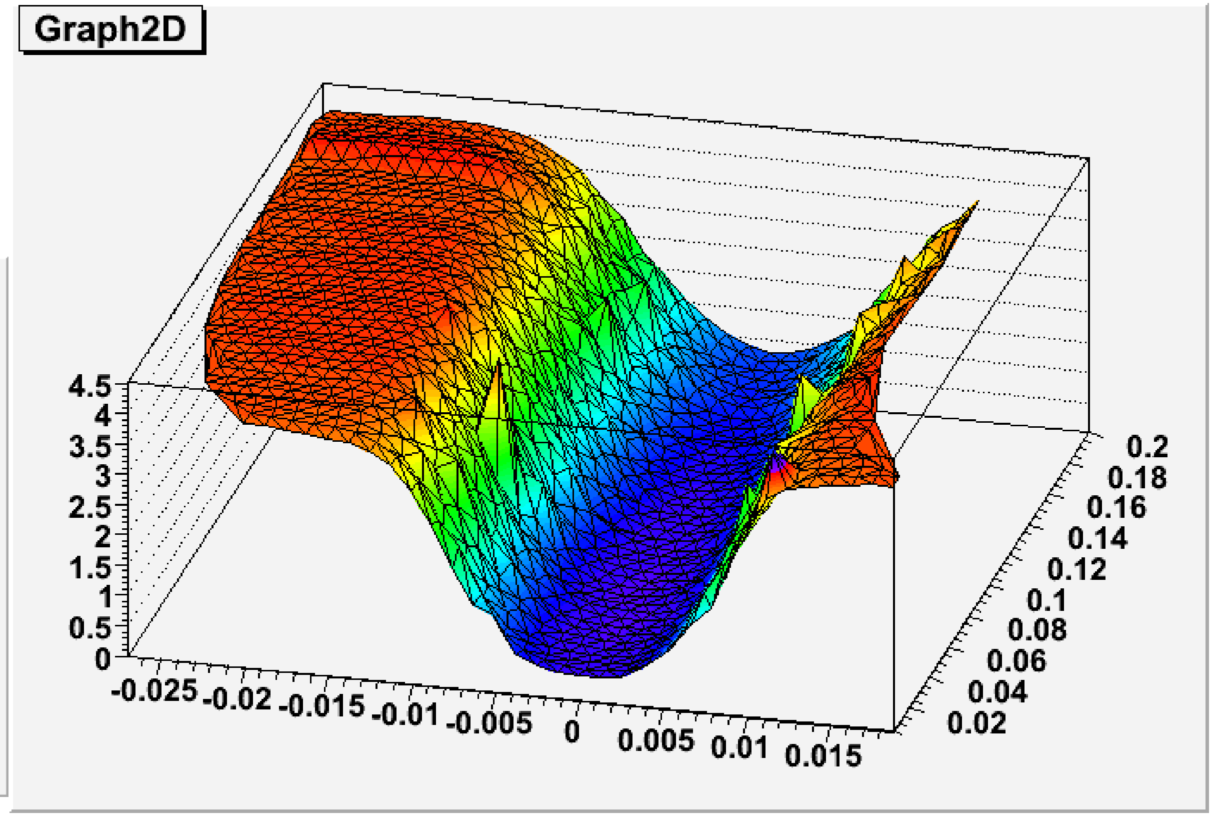
Set of standard tests and analysis: focusing, strip response, charge sharing



Detail of looking of minima (flat in 60μm range)

Example of focusing matrix





Width of green area indicate focusing width of laser beam

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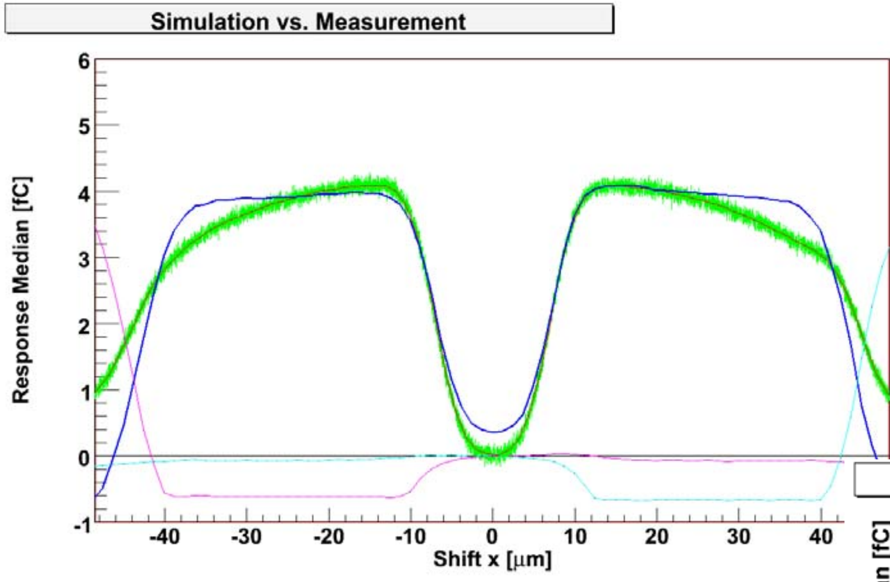
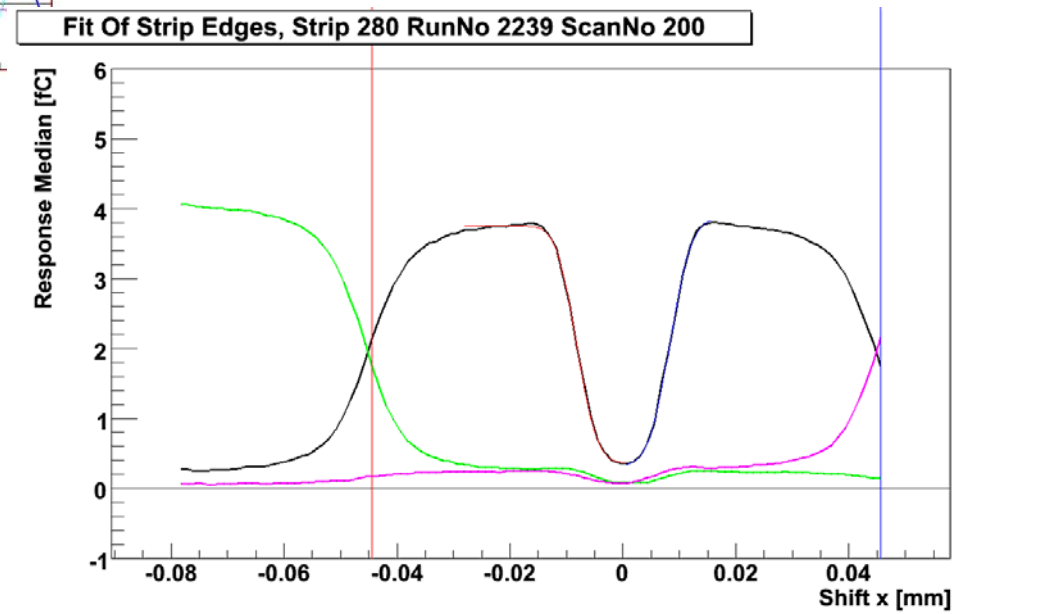
Different wavelengths: 650nm and 1060nm



CiS detector: 650 wavelength, differences from simulations, negative charge induced in neighbored



CiS detector: 1060 wavelength – in very good agreement with simulations

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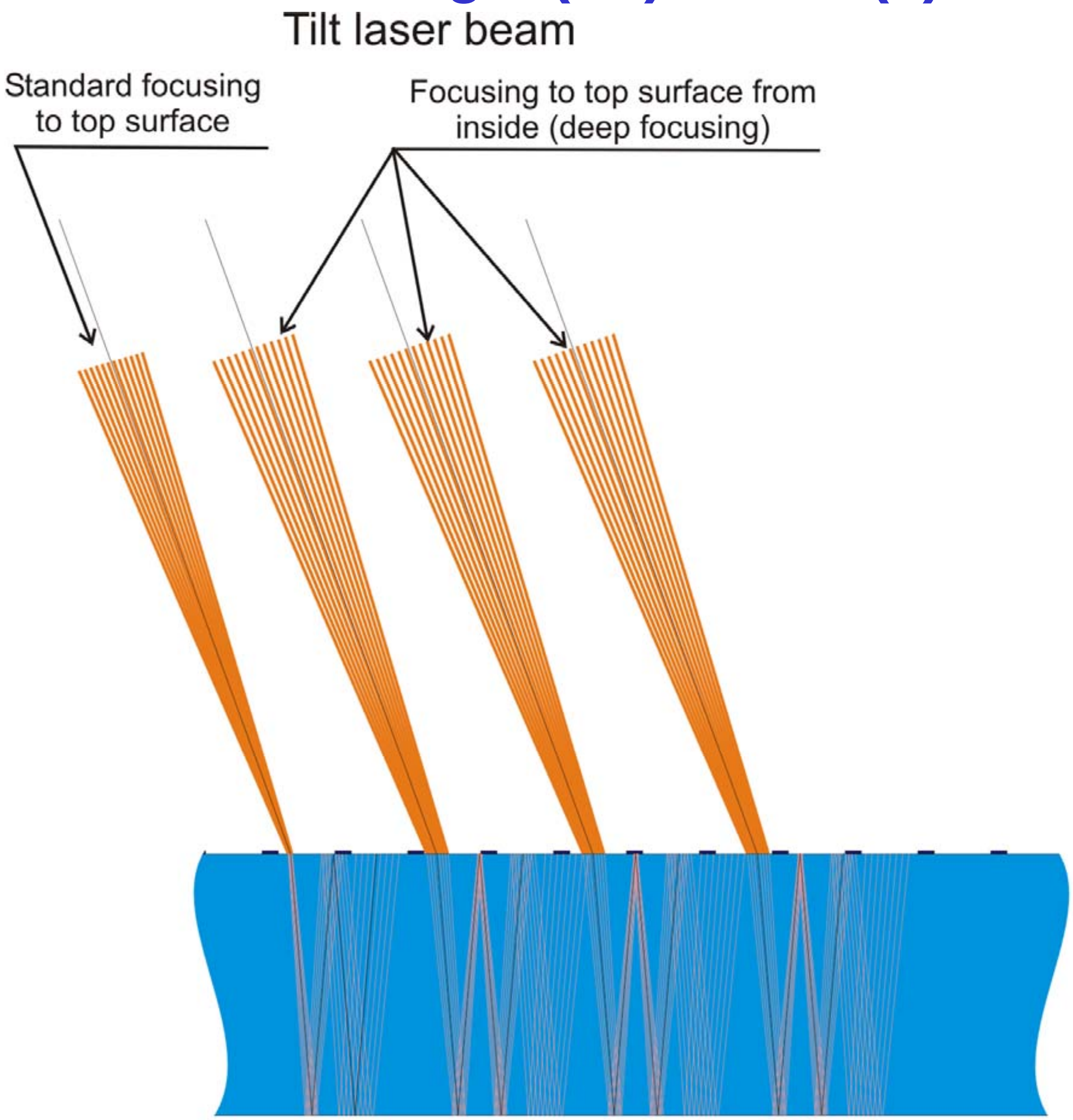
Angle (tilt) scans (1)



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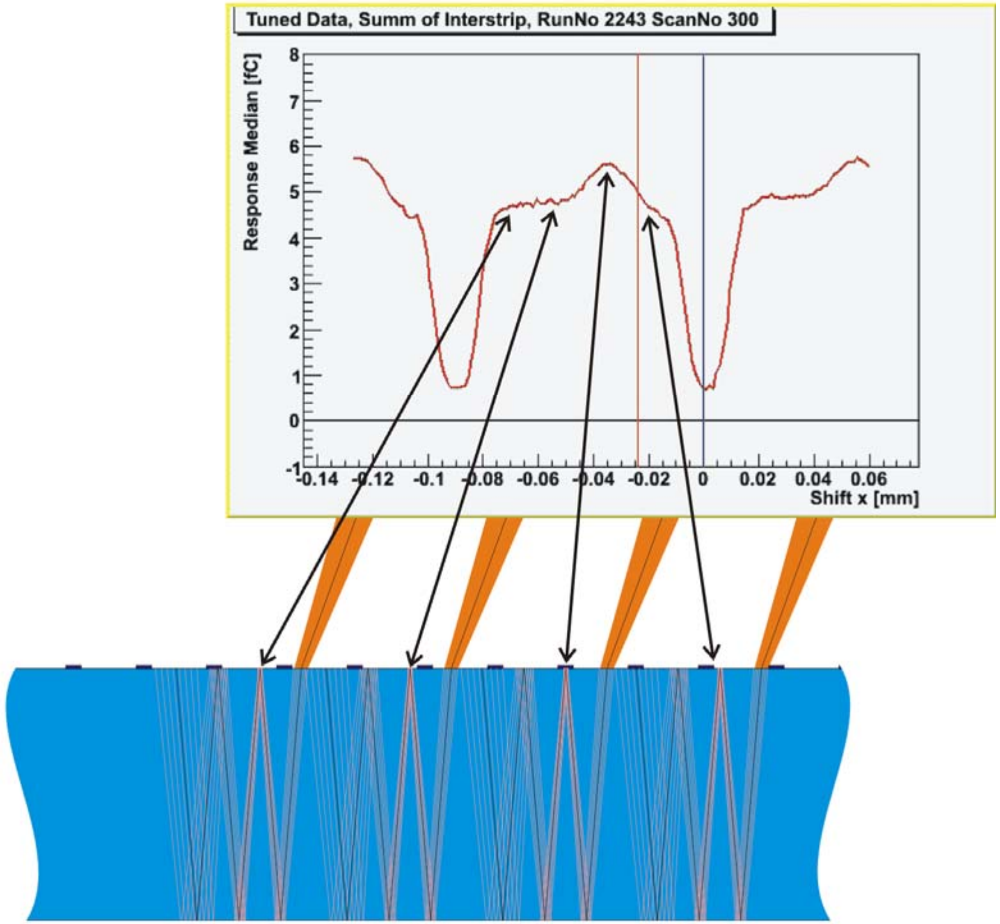
Angle (tilt) scans (2)

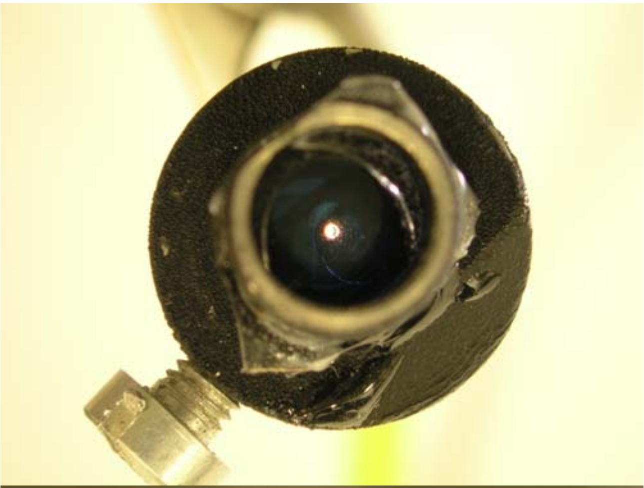
Tilt laser beam

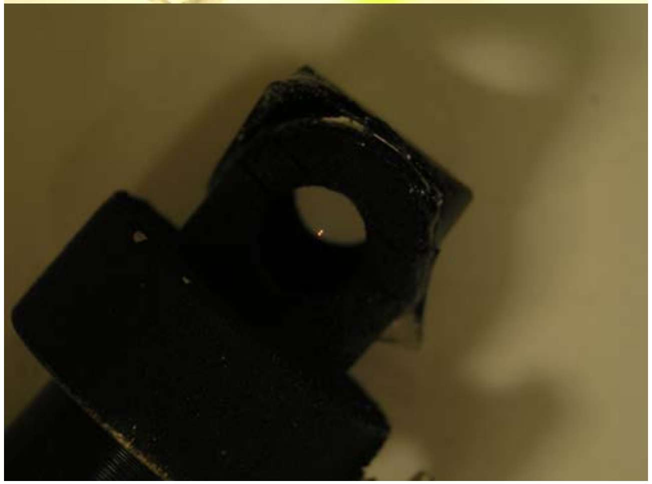
Focusing to top surface from
inside (deep focusing)

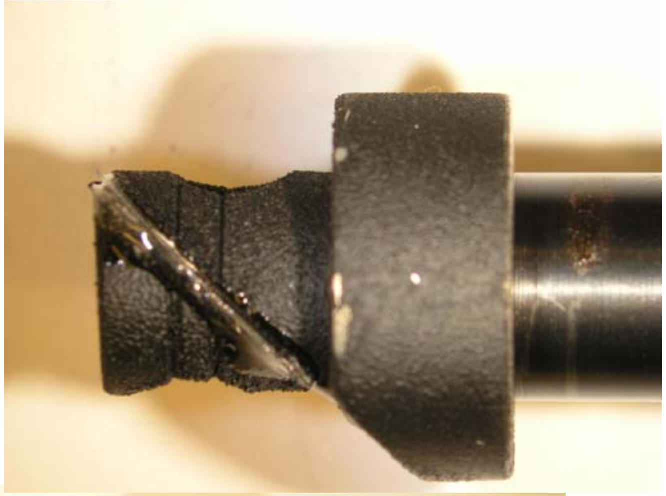


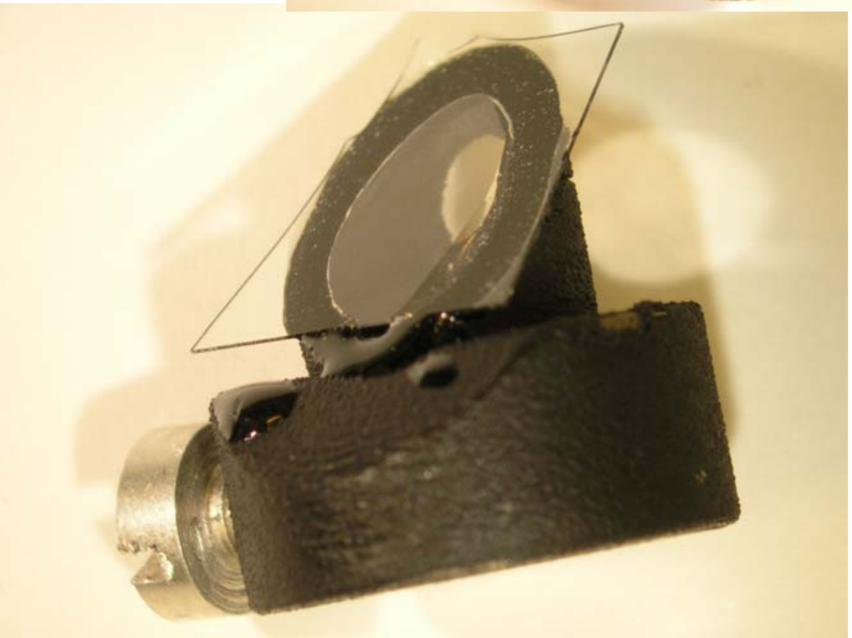
Optical head for power monitoring and reflectance measurement

1. Mechanical design and manufacturing done
2. Readout electronics under construction









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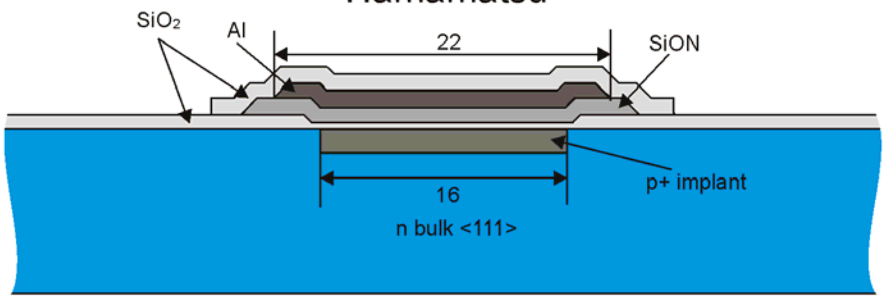
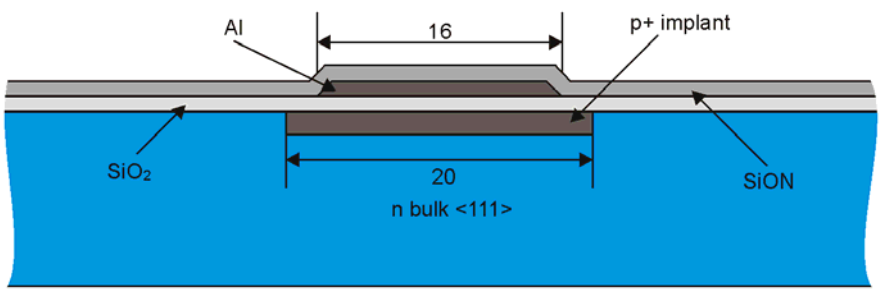
Deeper understanding of laser beam interaction with Si detectors

Surface structure on strip

Hamamatsu

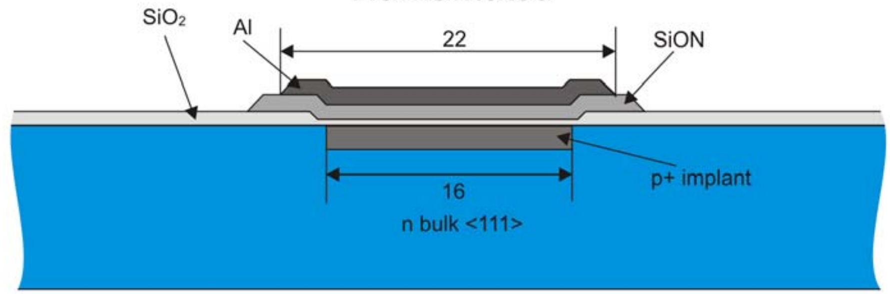


CiS

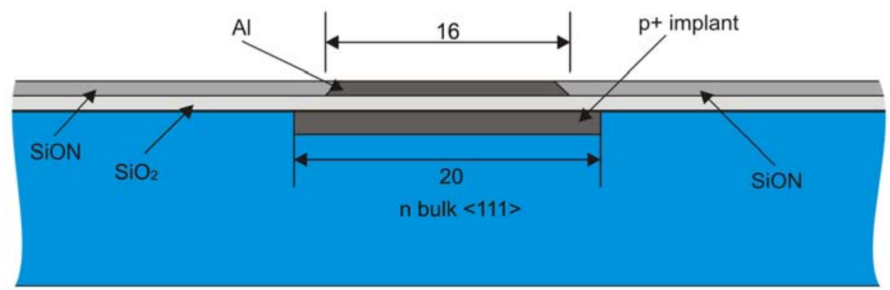


Surface structure on bond pad

Hamamatsu



CiS



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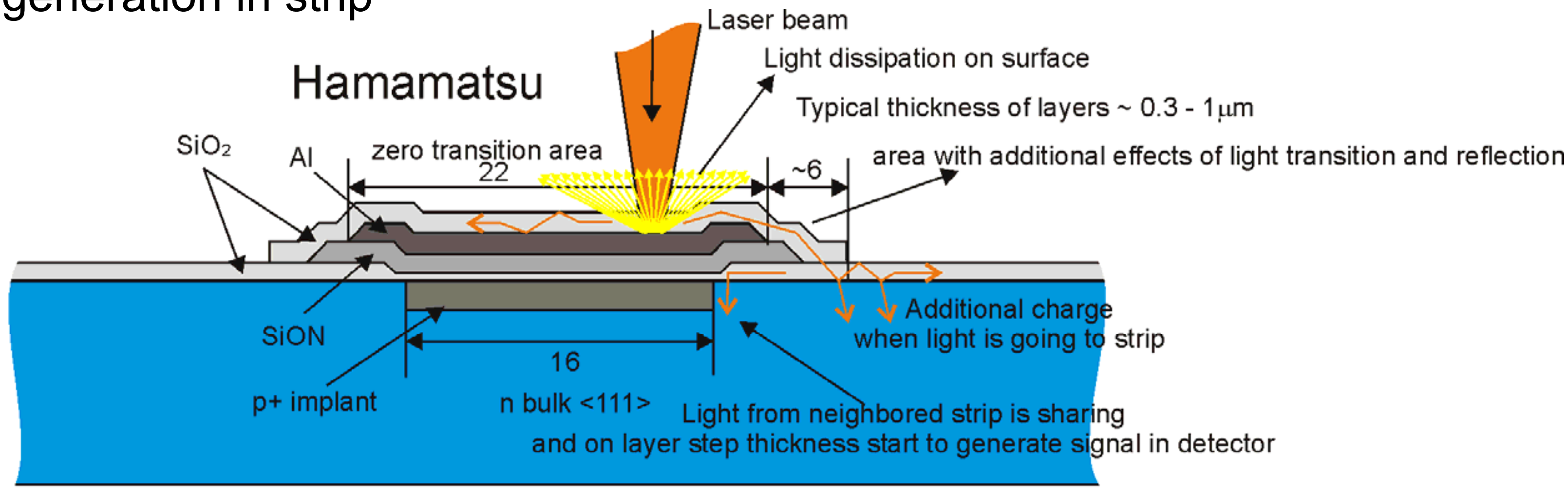
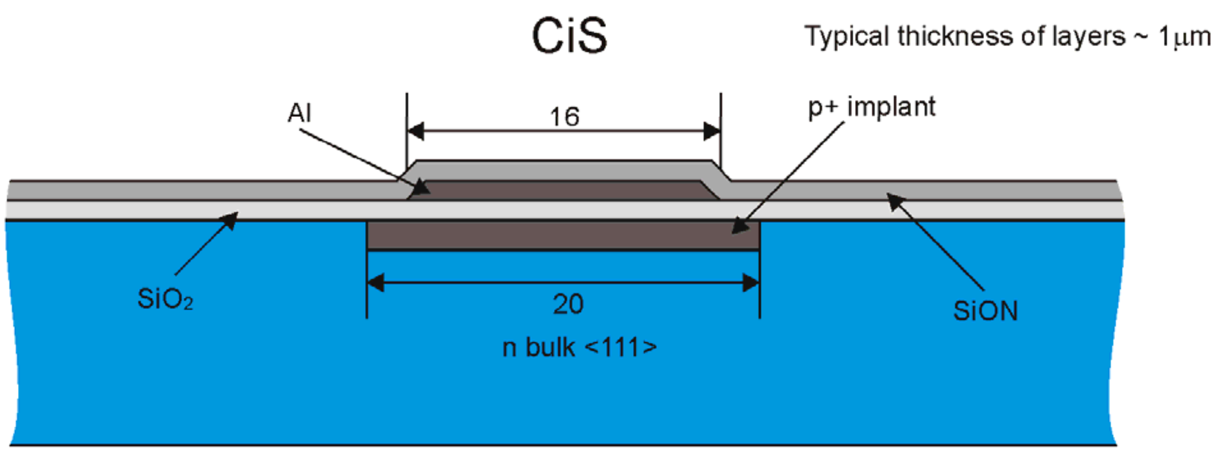
Deeper understanding of laser beam interaction with Si detectors

Charge generation in strip





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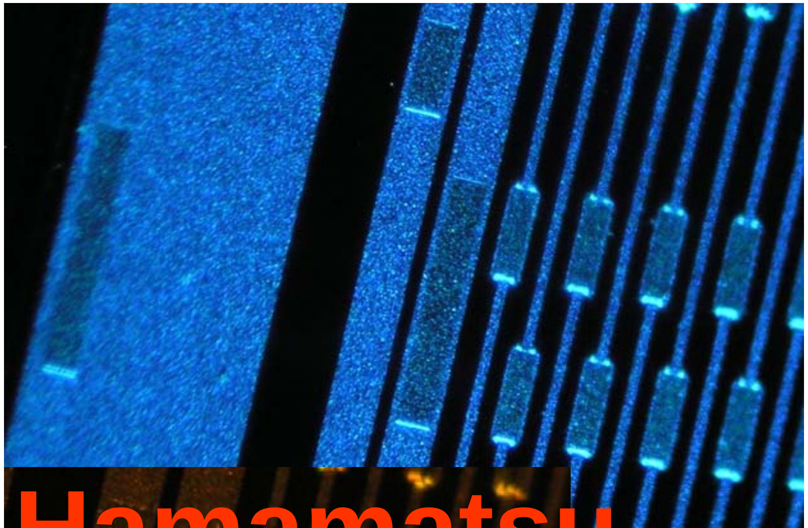
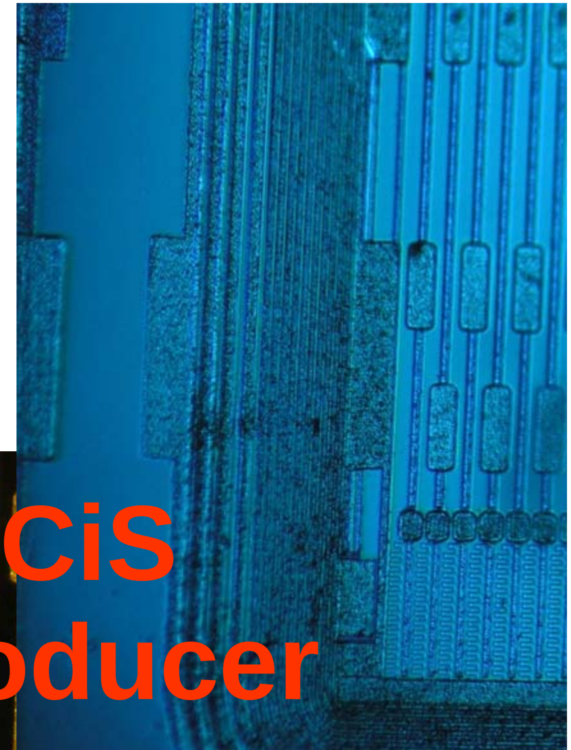
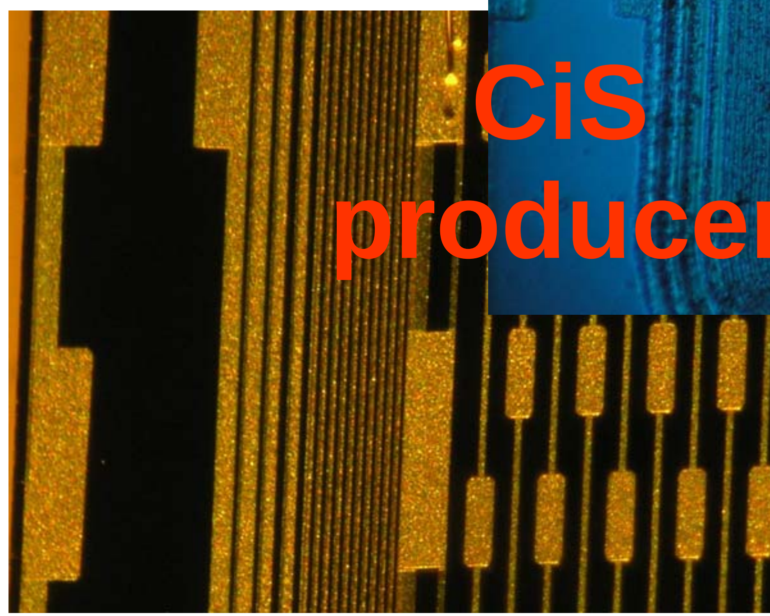
Deeper understanding of laser beam interaction with Si detectors




1. Surface
2. Coating
3. Thickness
4. Size
5. Technology

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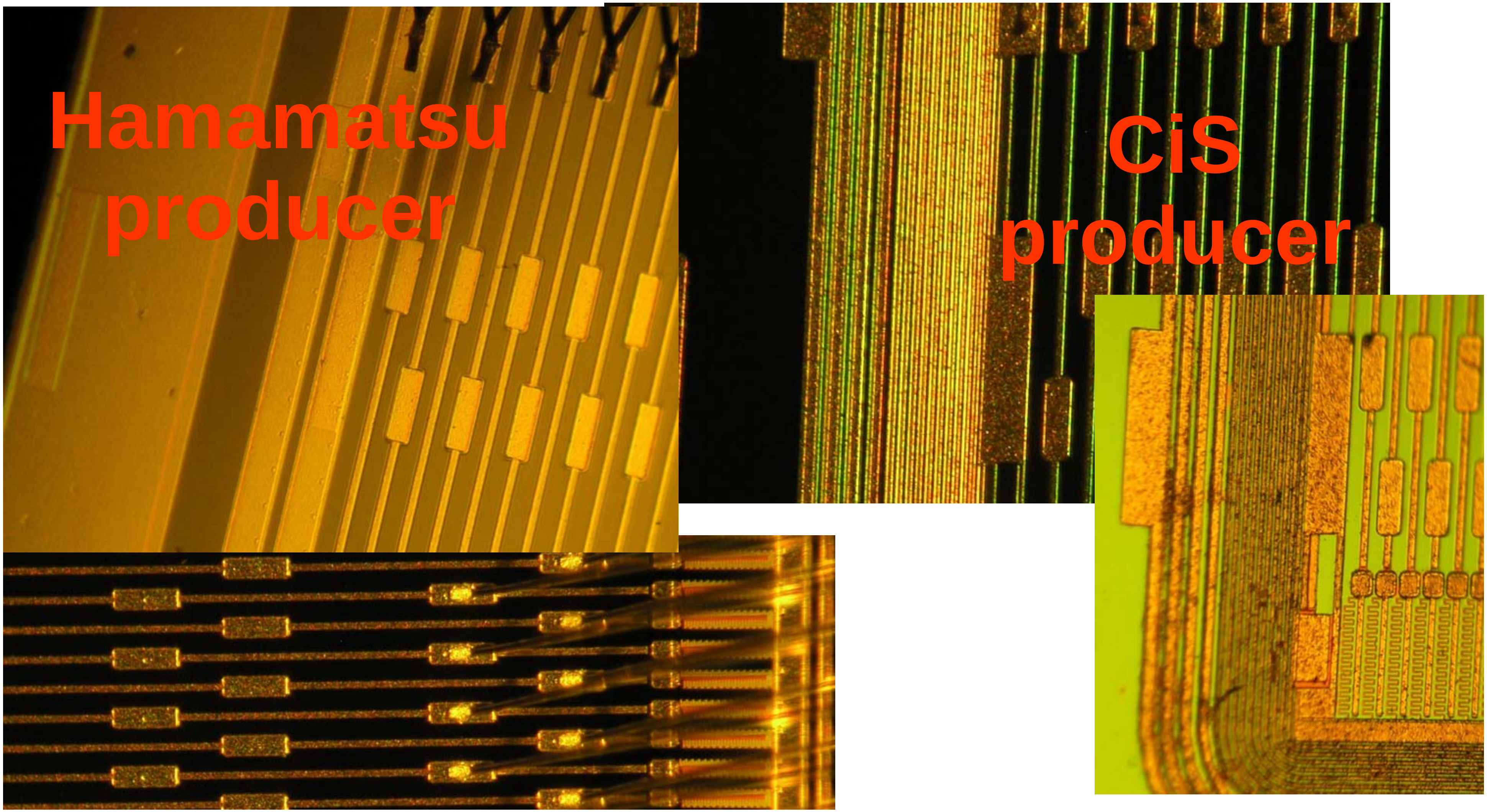
Deeper understanding of laser beam interaction with Si detectors



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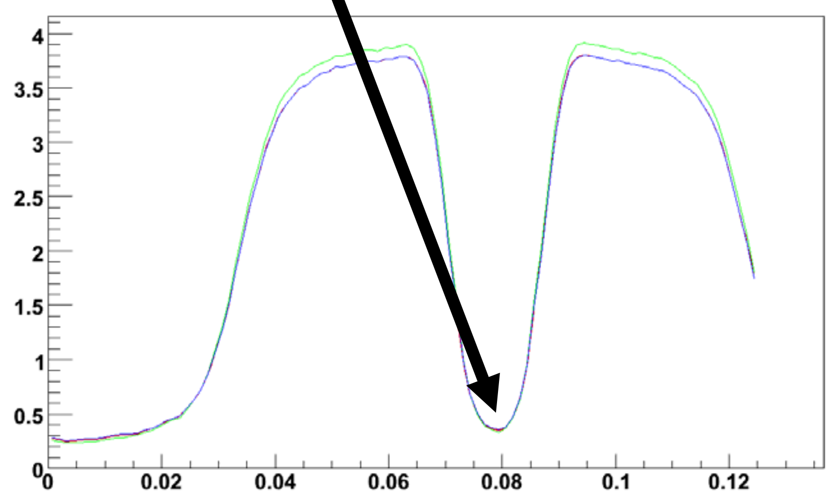
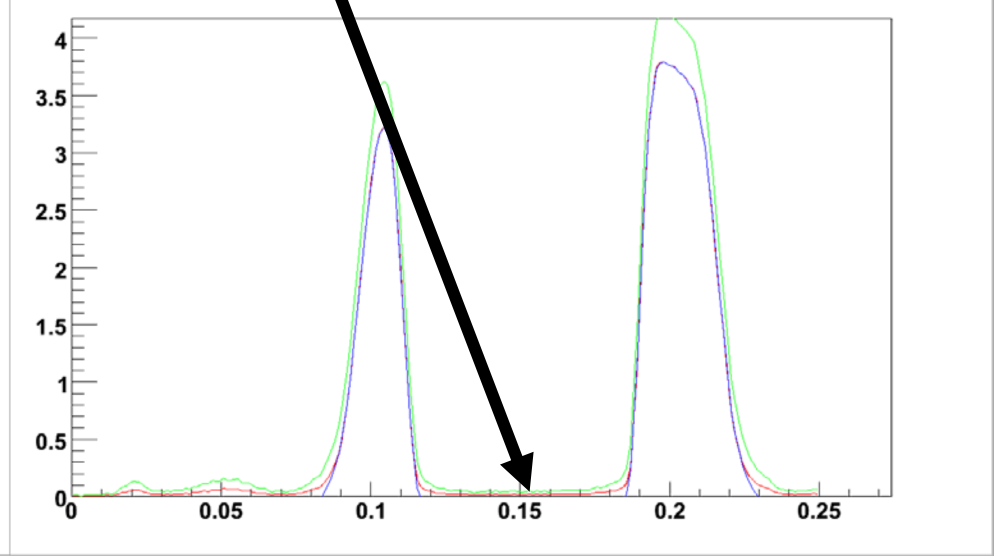
Deeper understanding of laser beam interaction with Si detectors

CiS producer

Response on strip with residuum charge sharing in protecting layer

Response on bond pad with no protection layers





Deeper understanding of laser beam interaction with Si detectors

- Next possible effects influencing laser tests:
  - For 1060nm wavelength – thickness of silicon substrate changes: minima-maxima on interferences gives about 30% changes in charge collection in ½ wavelength inside Si (~150nm) – only in large area scans
  - For 650nm not fully depleted silicon in collecting time range – charge is created in layer <4μm in pure electric field – depended also of properties of coating layers (electric field gradients, conductivities, lost charge vacancies,…)
  - Irradiation effects: additional diffusions, unhomogeneities

DST data format for test beams prepared

See second talk about design of DST data format for beam tests

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Future plans/fields of interest

1. Participation on beam tests and their analysis
    1. Telescope preprocessing
    2. DAQ program participation
    3. DST creation in ROOT format
    4. Macros for reading and evaluation of DST
2. Laboratory tests
    1. Continuing on laser test of response of detector
    2. Continuing on automation of laser tests (voltage scans, position scans)
3. Programming activities
    1. Preparation and maintenance of standard test analysis framework for data evaluation in ROOT
4. New fellow start on SiLC in Prague
    1. Dr. Peter Kvasnička start in August 2006
5. Linear collider detector simulation (both performance and microscopic)
    1. Summer 2006 start activities on this field – PhD student Zbyněk Drásal

Backup slides

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Comparisons

Tests on beam <-> beta tests <-> laser tests

- Tests on beam of high energy particles (beam tests):

  Most similar conditions to real experiment

  Available only few times in year and complicated organization

  High cost

- Tests used β particles from radioactive sources:

  Lower cost and good availability, used real particles

  Wide spectra of energies without their measurement possibility

  Unknown interaction point between particle and sensor, no space resolution information

- Tests with laser light:

  Exact precise space resolution, lower cost, good availability

  Depth penetration setting using different light energy (wavelength)

  Complication on absolute efficiency measurement from energy from photon beam

Laser tests

Basic differences between particles and light beam in silicon:

- laser tests used beam of light with nonzero width
- different method of electron generation

Some effects missing:

- δ – drift electrons
- energy of particles

Some effects added:

- primary and secondary reflections

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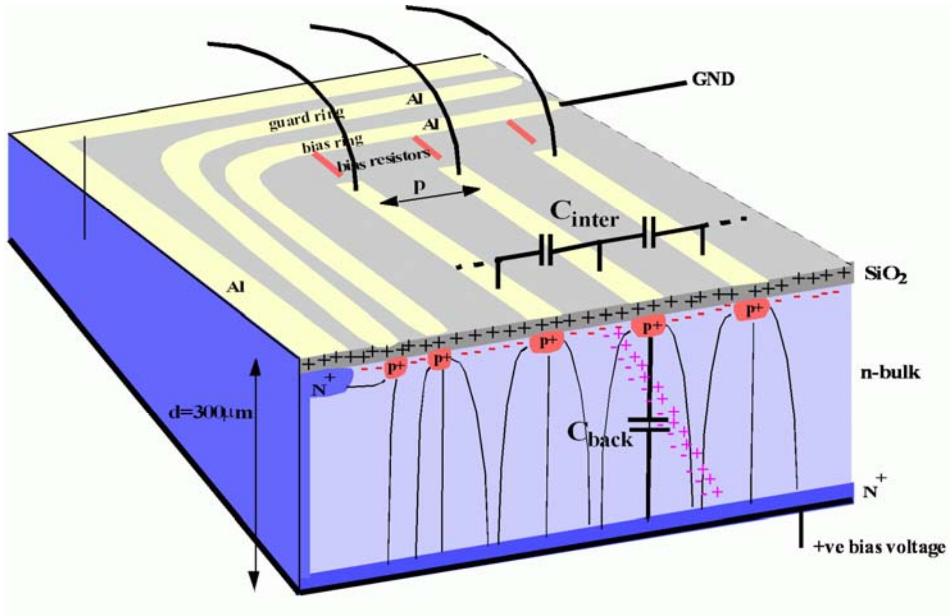
Silicon Microstrip Detector

Principle:

- ➢collection of charge released in the depleted volume of a reverse biased diode
- ➢spatial resolution through segmentation of diode
- ➢p strips on n substrate
- ➢AC coupling to keep leakage current away from read-out electronics
- ➢biasing through polysilicon or implanted resistors
- ➢Irradiation in SCT volume up to **1.2×10^{14} 1-MeV-n/cm^2 for 10 years** of LHC running

Properties:

- ➢leakage current
- ➢depletion voltage and substrate resistivity
- ➢interstrip capacitance
- ➢backplane capacitance
- ➢crystal orientation
- ➢charge collection
- ➢signal to noise



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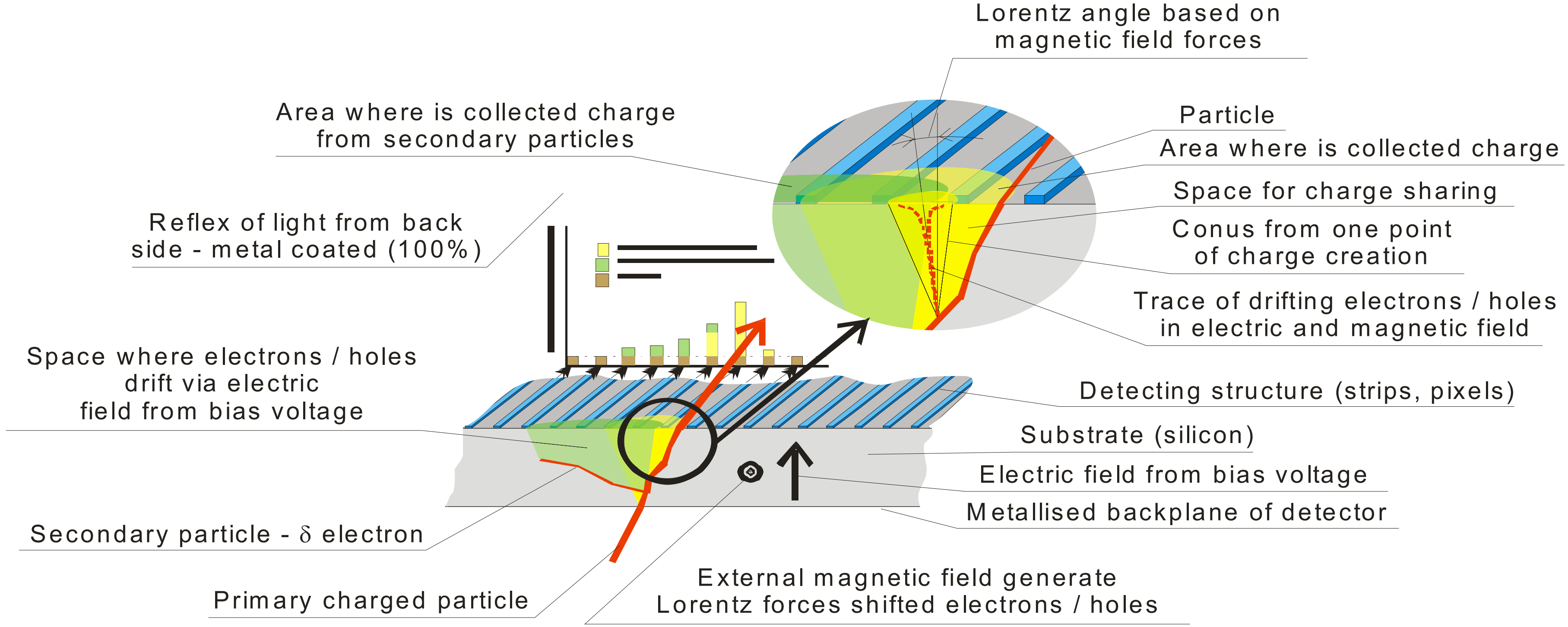
Charge generation in silicon induced by particles



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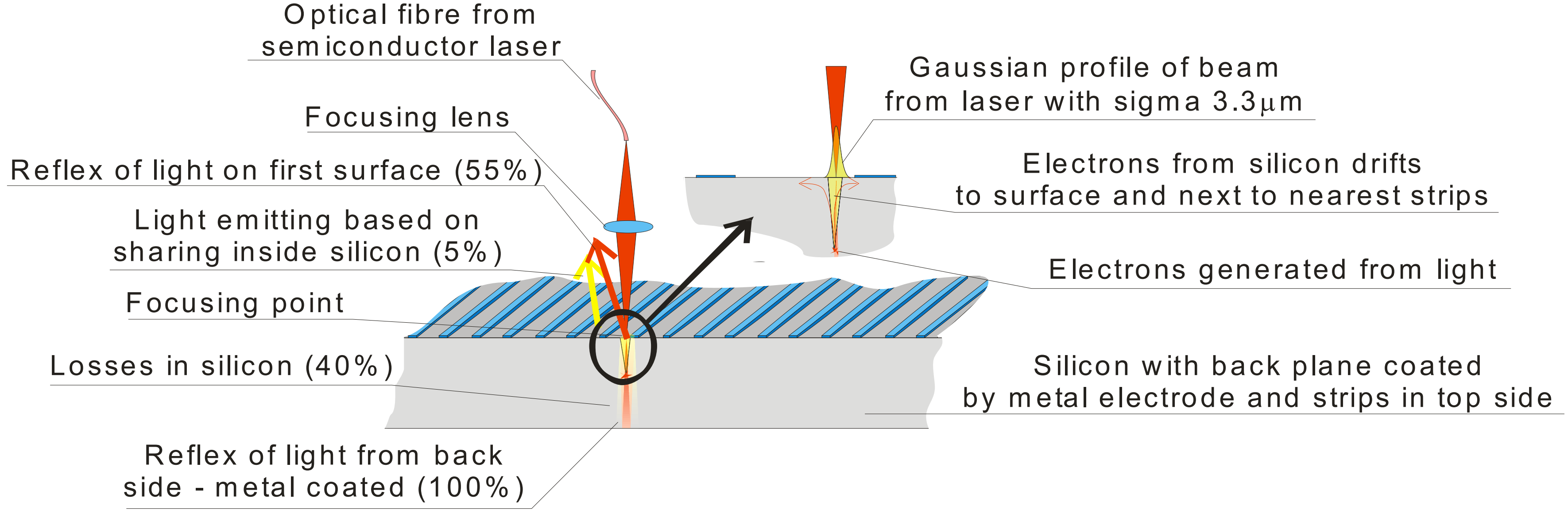
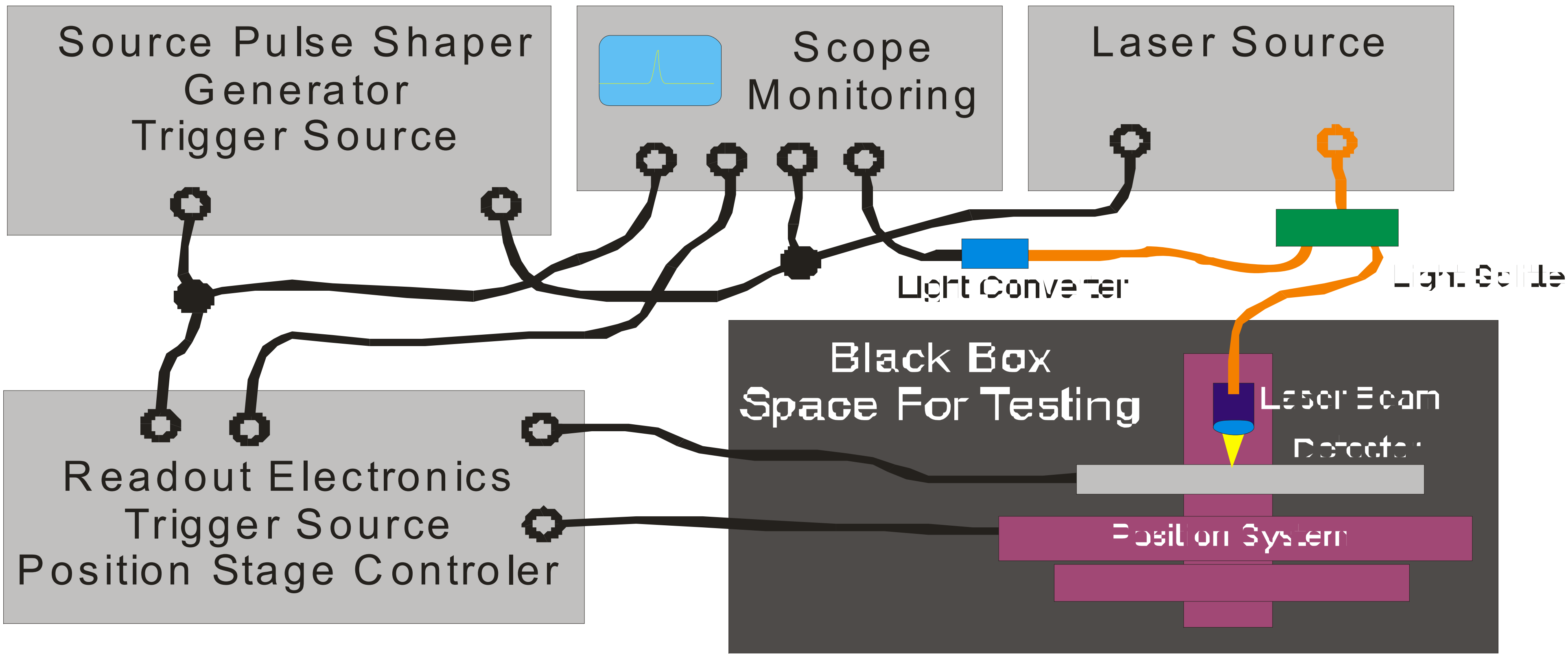
Charge generation in silicon induced by laser beam



Most typical arrangement of laser tests



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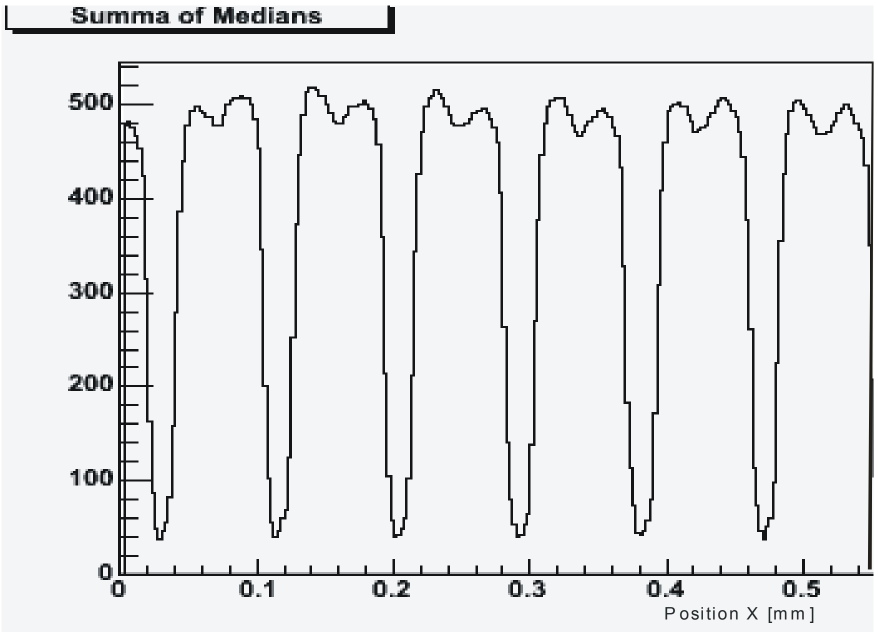
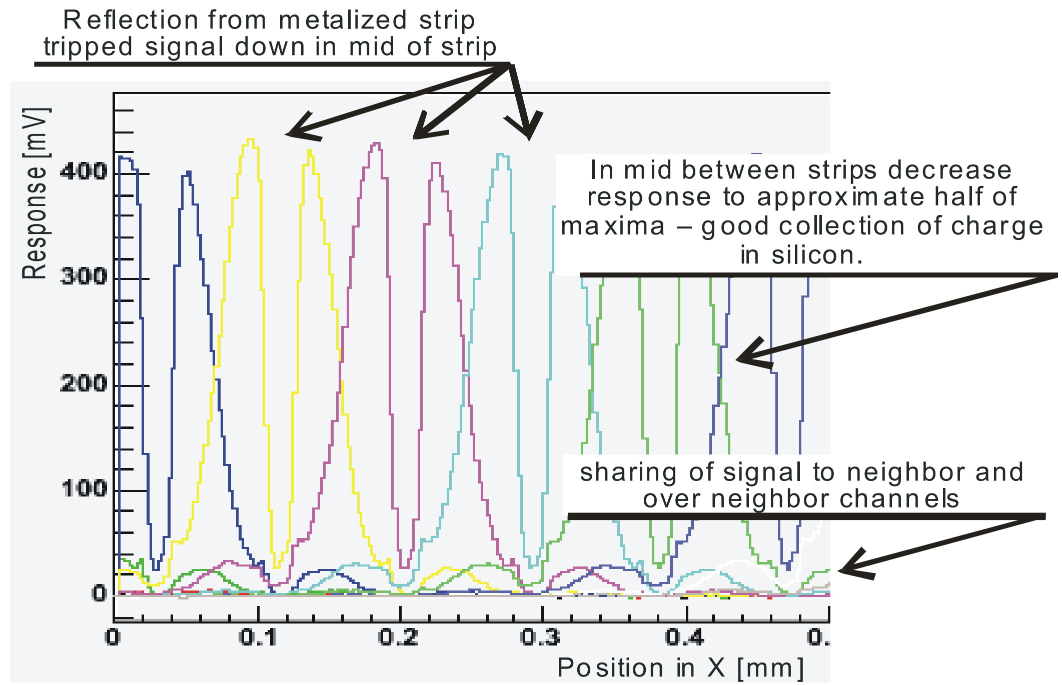
Response of testing modules



Sum of signal of 12 adjacent strips show that collected signal in one channel is 85% from whole collected charge in detector.



Typical response from few channels if laser beam moves across strips in best focused point.

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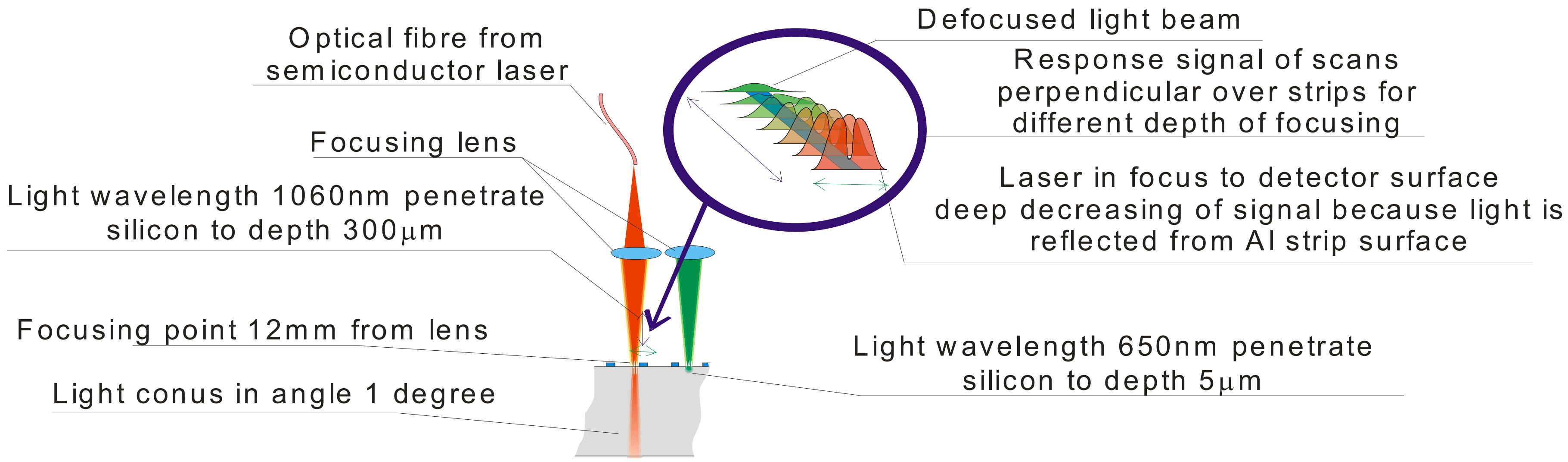
Laser tests - focusing



Principle used for laser focusing

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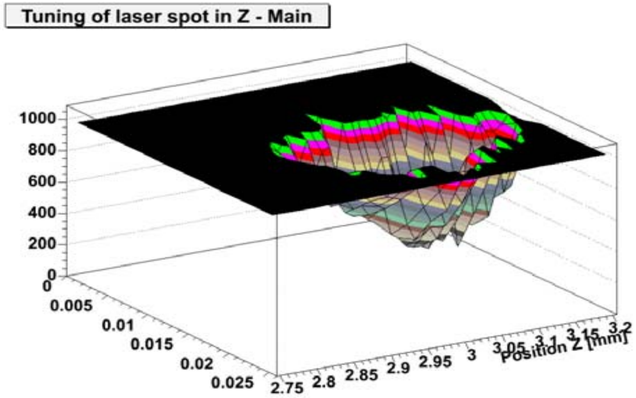
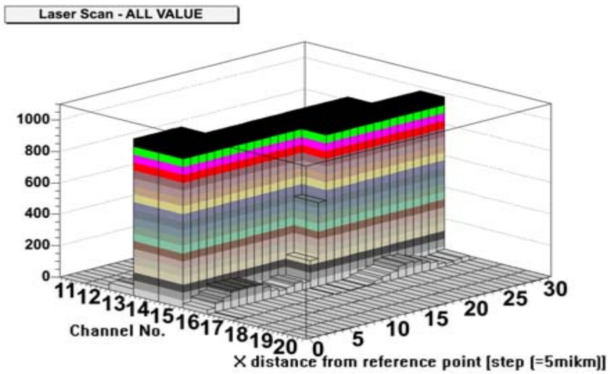
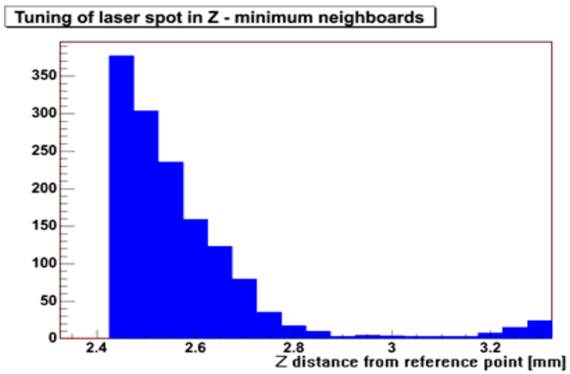
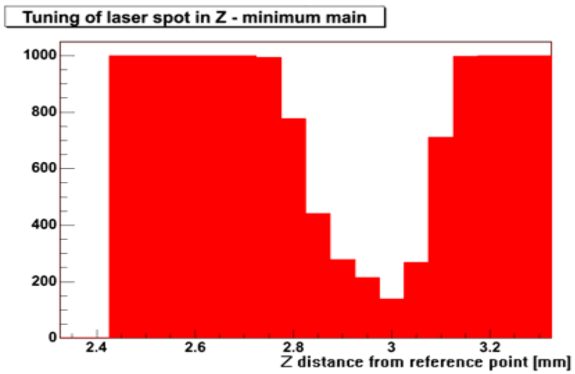
Laser tests - focusing



Main conclusion: there is possibility to tune laser focusing to smallest spot using reflectivity from strip metal material, sensitivity of focusing of our type of laser output is very high, focus range is less 50 μm (from factory is declared good focus range about 1 mm).





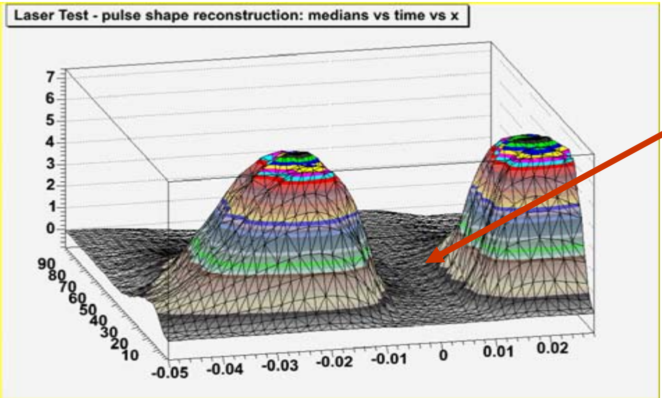


Laser Tests - Applications

Numerous tests of ATLAS end cap SCT modules were developed and performed:

- The bond mixing test done up to 30 minutes per detector – test for production modules
- The channels from mask file (bad channels) tested independently using two methods
- Punch through (pin hole) channels test (gain confirmation) for response
- Pulse shape reconstruction
- Test of homogeneity of response from detector in full area is possible
- Detail response vs. inter-strip position
- Bias scan of detectors
- Temperature scan
- Spatial resolution of noise bump-strips on CiS detectors was checked and measured

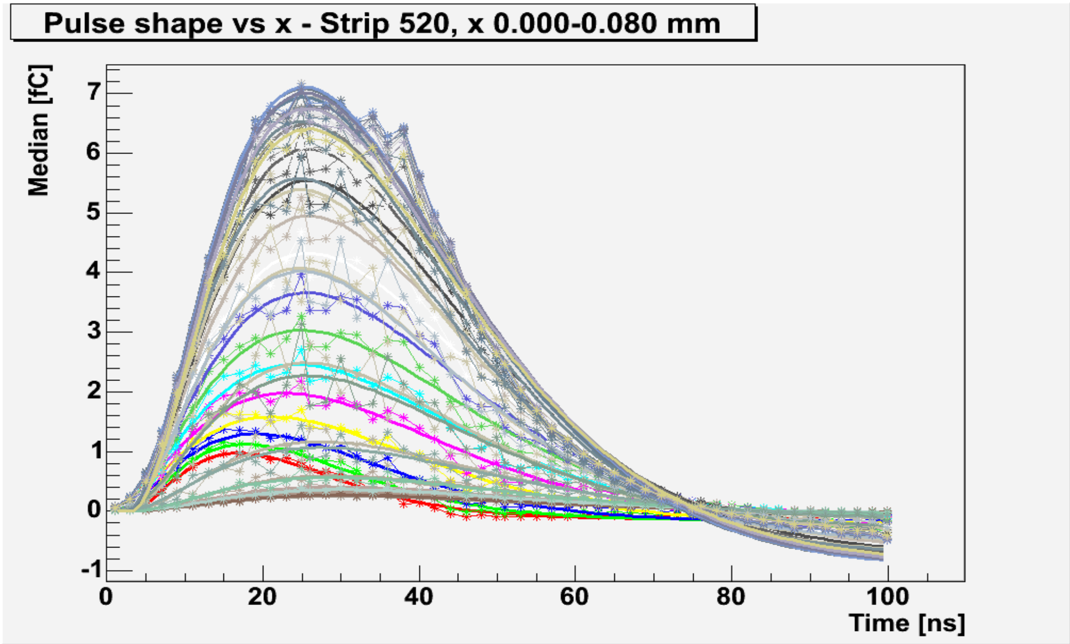
Pulse shape reconstruction



Strip position

2D graph of medians in time shift vs. x, strip metal part is on point 0 where practically whole light beam is reflected out

Pulse shape fit for all x positions



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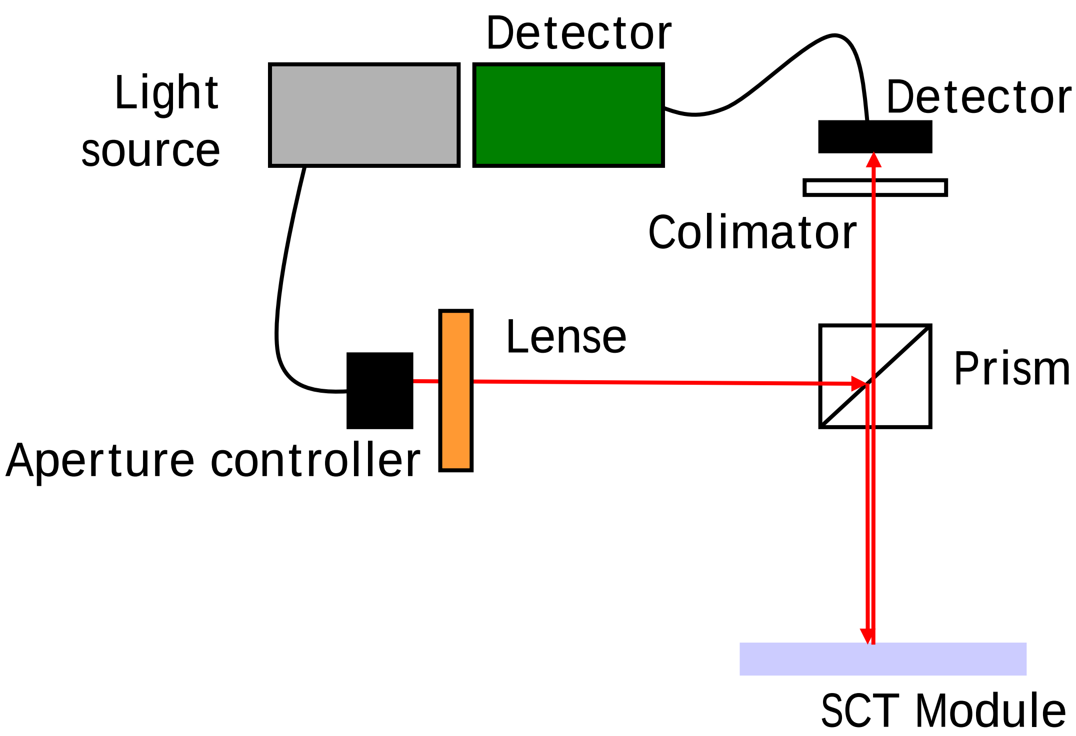
Reflectivity measurement



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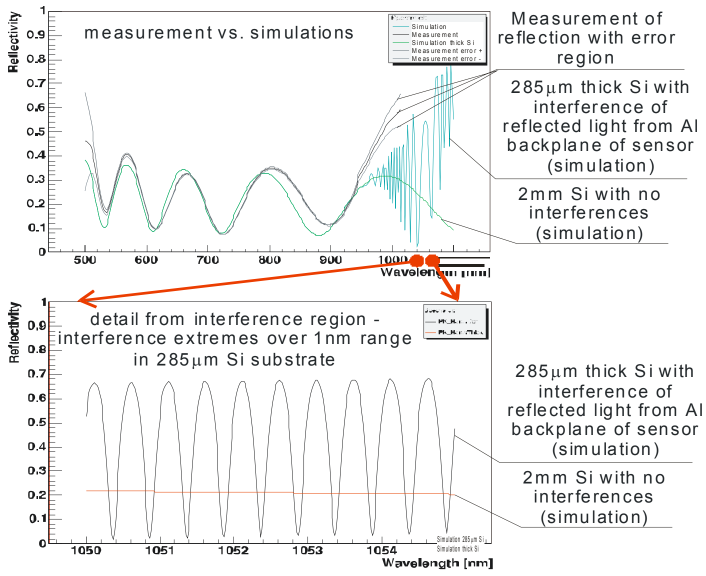
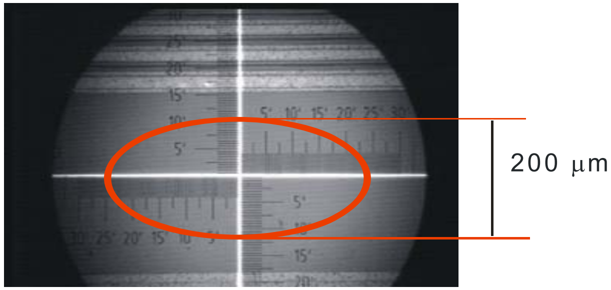
Optical properties



Plots comparing reflectivity measurement and calculation from thickness of layers in range 300 - 1100nm of wavelength

Absolute response measurements are problematic:
deposition of defined charge in the sensor is difficult because of many optical effects:
- part of light is reflected
- sometime transparent layers are not homogenous because technology of covering use also transport of atoms between layers so borders between layers are gradients and no steps
- refractive index for some materials must be measured because big spread of value depends of using deposition and surface polishing technology
- thick and transparent substrates gives hardly defined conditions for reflectivity calculation
- the best is use the same laser beam for also reflectivity measurement (method of this is on the way)



Refractive index and thickness of layers was measured on spot in range 300 - 800nm of wavelength.

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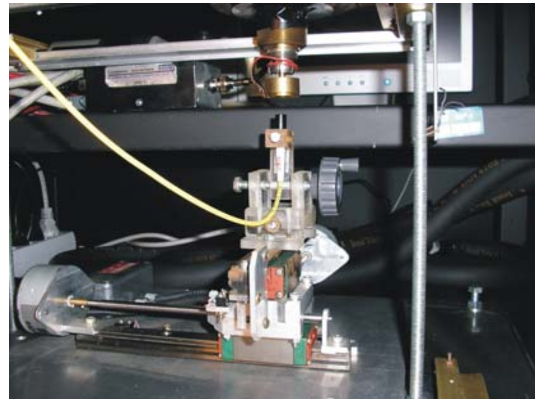
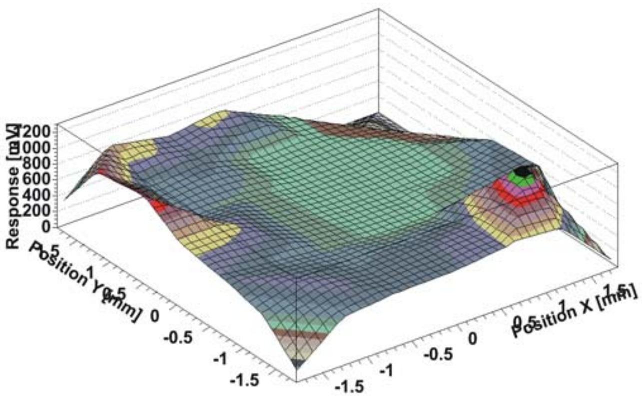
New Tests

- large area diodes tests
- depfet strustures

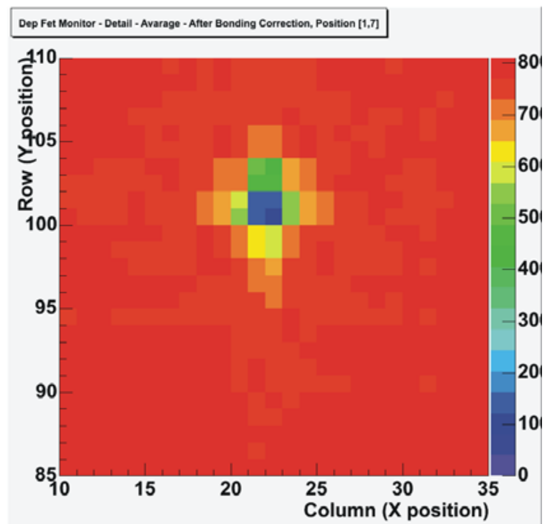
Stability of laser pulse:
Amplitude: σ < 1.5% @ 1.8MeV deposited
Timing jitter: σ < 0.4ns @ 32MeV deposited



Arrangement of tests



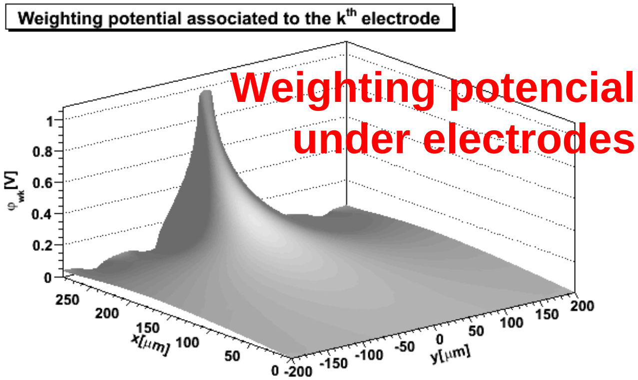
Response of Si pad detector for 1060nm light wavelength

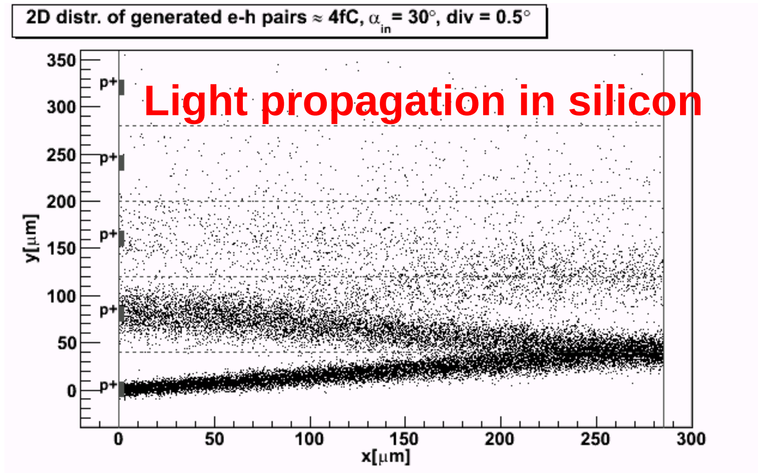


Response of DEPFET detector

Laser Tests And Simulations

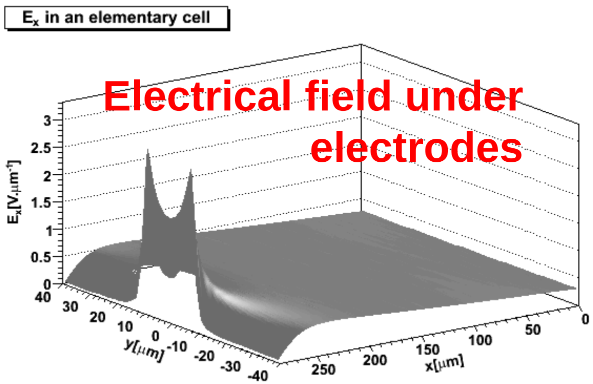
How is signal on detector created

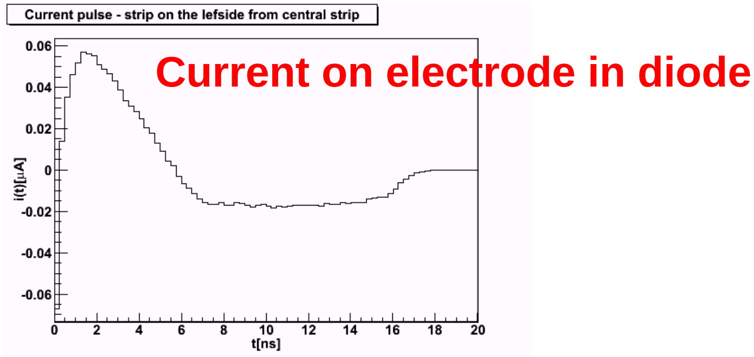




Cooperation:

- University of Bari (Italy)
- Lappeenranta University of Technology (Finland)





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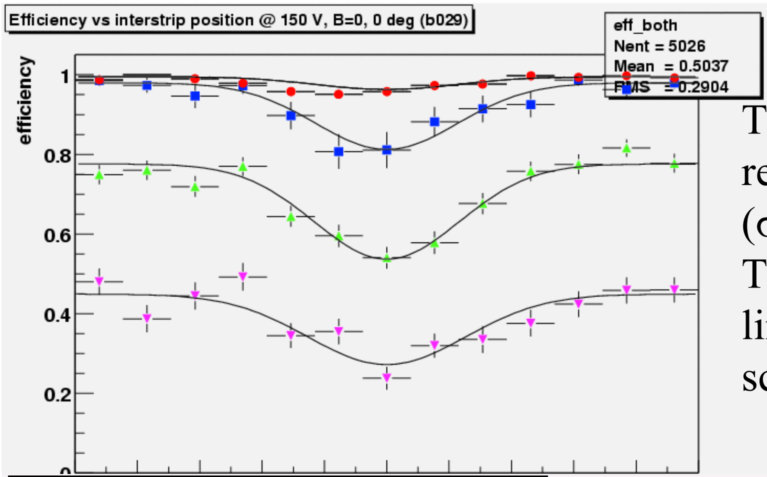
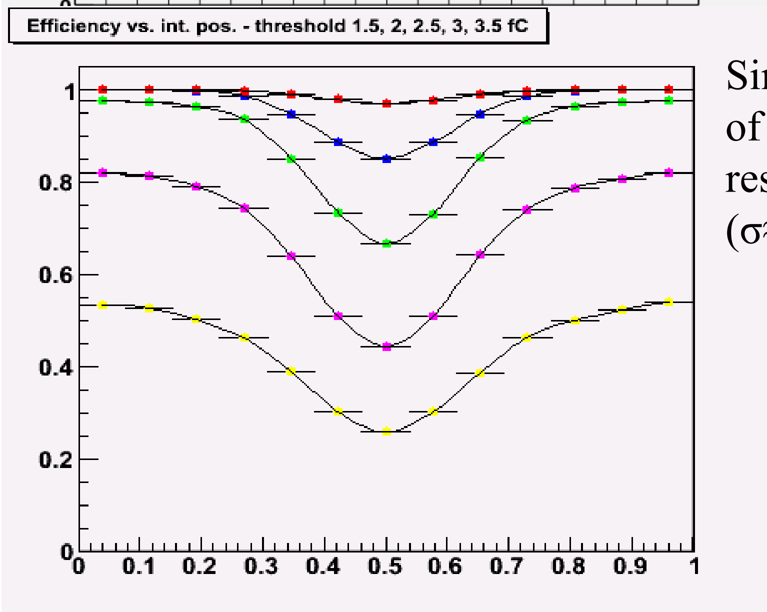
Space Resolutions Measurements

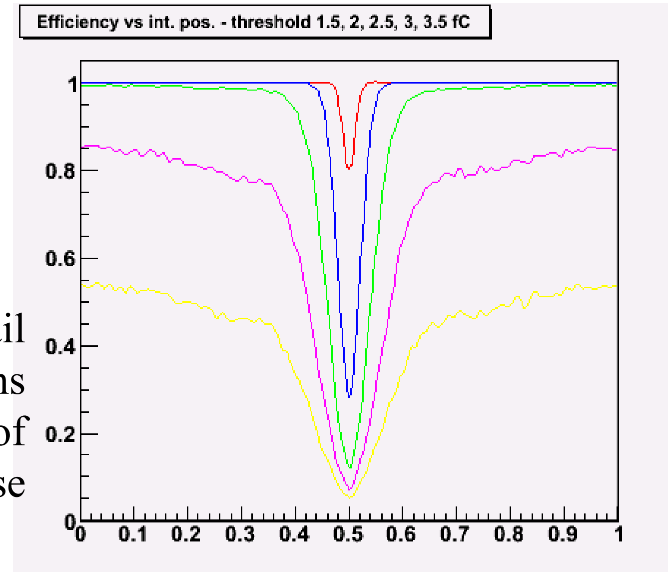


Test beam results (σ≈10μm) Telescope limitation & scattering

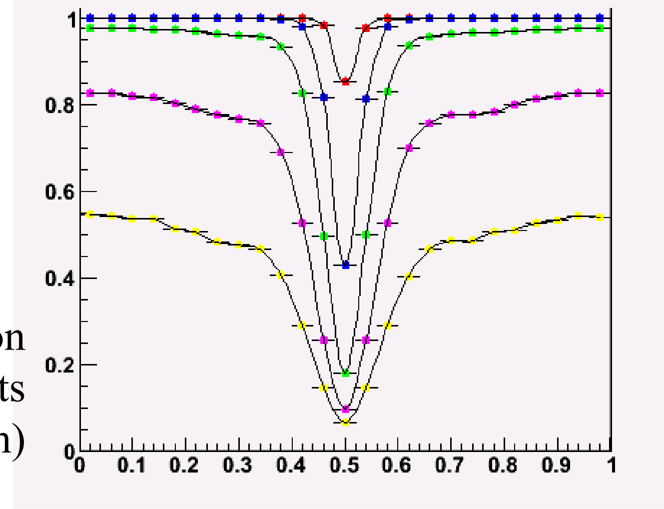


Simulation of test beam results (σ≈10μm)

Detail simulations (σ≈1μm) of response



Simulation of laser tests (σ≈4μm)



Cooperation

- Help in building of new laser test laboratories: MPI Mnichov, University Freiburg
- Looking for examples for testing around
- Cooperation with:
  - ÚRE AVČR Prague
  - University of Freiburg
  - MPI Mnichov
  - University of Bonn
  - University of Lancaster
  - University of Bari
  - Lappeenranta University of Technology

Conclusions

Laser tests are useful in:

- precise space resolution studies
- time walk and time shape measurements
- functionality of problematic part of detectors
- surface charge collection and deep charge generation from 4 mm@650nm up to 1mm@1060nm

Quality of tests depends from:

- top layers: thickness, refractive index, surface quality
- geometry of pads on top, their material, surface of them, protected layers
- laser light beam quality, coherent properties, long time stability, aperture, wavelength

Usability

Laser test are:

- extremely useful for tuning of individual sensor and readout settings to find optimal working parameters

- good for comparison between the same type of detectors with exactly the same top surface properties

- of limited use in absolute measurement of efficiency of semiconductor detectors (under study)

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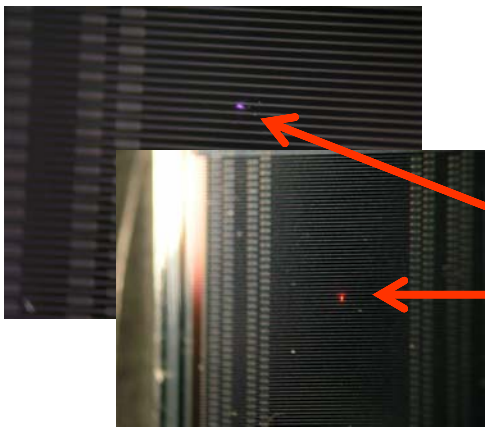
Place Of Laser Tests

Clean room in Prague Charles University with laser black box and readout electronics stands

Visual inspection place



Laser spot on detectors in 1060nm and 660 nm wavelength, strip pitch is 80 μm

Black box for laser test measurements

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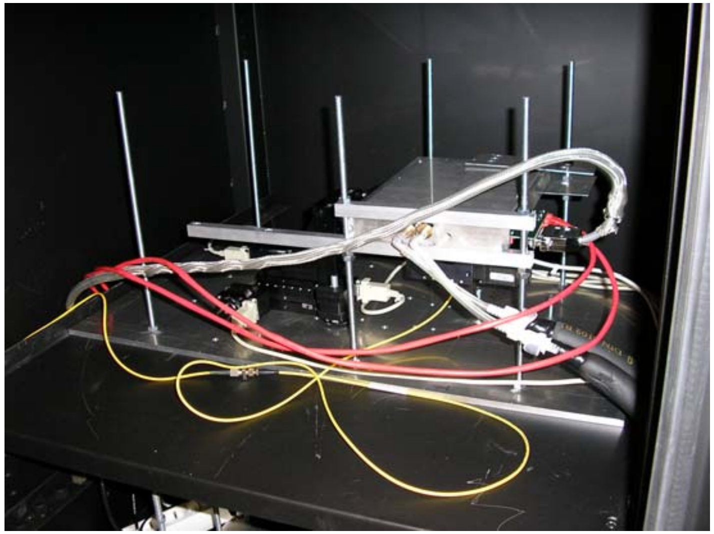
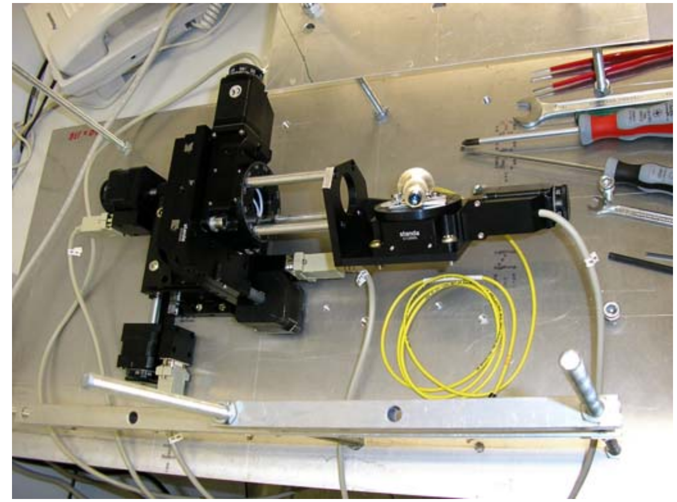
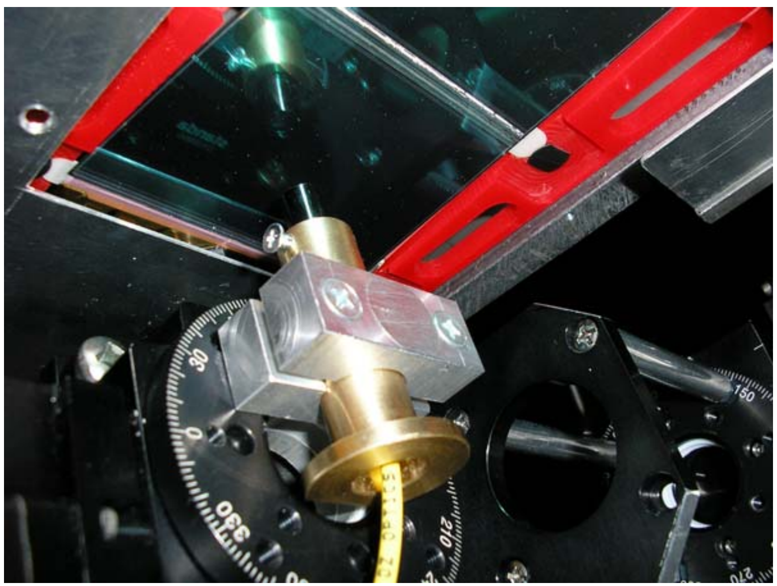
3D2R moving system

Arrange ment in black box



3D2R Laser System





Lighting to detector

Tilting of laser beam before mounting of detector